## **Product Preview**

# 64K x 16 Bit 3.3 V Asynchronous Fast Static RAM

The MCM6323A is a 1,048,576 bit static random access memory organized as 65,536 words of 16 bits. Static design eliminates the need for external clocks or timing strobes; CMOS circuitry reduces power consumption and provides for greater reliability.

The MCM6323A is equipped with chip enable  $(\overline{E})$ , write enable  $(\overline{W})$ , and output enable  $(\overline{G})$  pins, allowing for greater system flexibility and eliminating bus contention problems. Separate byte enable controls  $(\overline{LB})$  and  $\overline{UB})$  allow individual bytes to be written and read.  $\overline{LB}$  controls the 8 DQa bits, while  $\overline{UB}$  controls the 8 DQb bits.

The MCM6323A is available in a 400 mil small—outline J-leaded (SOJ) package and a 44-lead TSOP Type II package in copper leadframe for optimum printed circuit board (PCB) reliability.

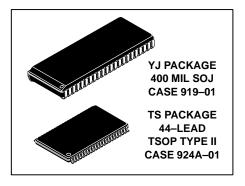
- Single 3.3 V ± 0.3 V Power Supply
- Fast Access Time: 10, 12, 15 ns
- Equal Address and Chip Enable Access Time
- · All Inputs and Outputs are TTL Compatible
- Data Byte Control
- Fully Static Operation
- Power Operation: 140/135/130 mA Maximum, Active AC
- Industrial Temperature Option: 40 to + 85°C Part Number: SCM6323AYJ10A

#### **BLOCK DIAGRAM** OUTPUT G HIGH BYTE OUTPUT ENABLE **ENABLE BUFFER** LOW BYTE OUTPUT ENABLE HIGH DQb **BYTE** ADDRESS OUTPUT ROW COLUMN **BUFFERS** 16 DECODER **BUFFER** DECODER HIGH BYTE CHIP WRITE **ENABLE** DRIVER **BUFFER SENSE** 64K x 16 16 **AMPS** BIT WRITE LOW **MEMORY** BYTE **ENABLE ARRAY** OUTPUT BUFFER **BUFFER** LOW **BYTE** WRITE BYTE DRIVER ŪΒ **ENABLE** HIGH BYTE WRITE ENABLE **BUFFER** LOW BYTE WRITE ENABLE

This document contains information on a new product under development. Motorola reserves the right to change or discontinue this product without notice.

#### REV 1 10/17/97

## **MCM6323A**



PIN	ASSIGN	IMENT
А	1 •	44 D A
А□	2	43 🛘 A
А□	3	42 D A
А□	4	41 🛭 🖫
А□	5	40 D UB
ĒC	6	39 D LB
DQa 🛭	7	38 DQb
DQa 🛚	8	37 DQb
DQa 🛚	9	36 DQb
DQa 🛚	10	35 DQb
v <sub>DD</sub> [	11	34 D V <sub>SS</sub>
v <sub>SS</sub> [	12	33 D V <sub>DD</sub>
DQa 🛚	13	32 DQb
DQa 🛭	14	31 DQb
DQa 🛭	15	30 DQb
DQa 🛭	16	29 DQb
W C	17	28 D NC
А□	18	27 A
А□	19	26 A
А□		25 A
Α 🗆	21	24 D A
NC [	22	23 NC



## **TRUTH TABLE** (X = Don't Care)

Ē	G	W	LB	ŪB	Mode	V <sub>DD</sub> Current	DQa's	DQb's
Н	Х	Х	Х	Х	Not Selected	I <sub>SB1</sub> , I <sub>SB2</sub>	High-Z	High-Z
L	Н	Н	Х	Х	Output Disabled	I <sub>DDA</sub>	High-Z	High-Z
L	Х	Х	Н	Н	Output Disabled	I <sub>DDA</sub>	High-Z	High-Z
L	L	Н	L	Н	Low Byte Read	I <sub>DDA</sub> D <sub>out</sub>		High-Z
L	L	Н	Ι	L	High Byte Read	I <sub>DDA</sub> High–Z		D <sub>out</sub>
L	L	Н	┙	L	Word Read	I <sub>DDA</sub>	D <sub>out</sub>	D <sub>out</sub>
L	Х	L	L	Н	Low Byte Write	I <sub>DDA</sub>	D <sub>in</sub>	High-Z
L	Х	L	Η	Ĺ	High Byte Write	I <sub>DDA</sub>	High–Z	D <sub>in</sub>
L	Х	L	L	L	Word Write	I <sub>DDA</sub>	D <sub>in</sub>	D <sub>in</sub>

#### **ABSOLUTE MAXIMUM RATINGS** (See Notes)

Rating		Symbol	Value	Unit
Supply Voltage		$V_{DD}$	- 0.5 to + 4.6	V
Voltage on Any Pin		V <sub>in</sub>	– 0.5 to V <sub>DD</sub> + 0.5	V
Output Current per Pin		l <sub>out</sub>	± 20	mA
Package Power Dissipation		PD	.75	W
Temperature Under Bias	Commerial Industrial	T <sub>bias</sub>	– 10 to + 85 – 45 to + 90	°C
Operating Temperature	Commerial Industrial	T <sub>A</sub>	0 to + 70 - 40 to + 85	°C
Storage Temperature		T <sub>stg</sub>	– 55 to + 150	°C

NOTES:

- Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPER-ATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.
- 2. All voltages are referenced to VSS.
- 3. Power dissipation capability will be dependent upon package characteristics and use environment.

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to these high–impedance circuits.

This CMOS memory circuit has been designed to meet the dc and ac specifications shown in the tables, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow of at least 500 linear feet per minute is maintained.

#### DC OPERATING CONDITIONS AND CHARACTERISTICS

 $(V_{DD} = 3.3 \text{ V} \pm 0.3 \text{ V}, T_{A} = 0 \text{ to } 70^{\circ}\text{C}, \text{ Unless Otherwise Noted})$  $(T_A = -40 \text{ to } + 85^{\circ}\text{C for Industrial Temperature Offering})$ 

#### **RECOMMENDED OPERATING CONDITIONS**

Parameter	Symbol	Min	Тур	Max	Unit
Power Supply Voltage	$V_{DD}$	3.0	3.3	3.6	V
Input High Voltage	VIH	2.2	_	V <sub>DD</sub> + 0.3**	V
Input Low Voltage	V <sub>IL</sub>	- 0.5*	_	0.8	V

 $<sup>^*</sup>$  V<sub>IL</sub> (min) = - 0.5 V dc; V<sub>IL</sub> (min) = - 2.0 V ac (pulse width  $\leq$  20 ns) for I  $\leq$  20.0 mA.

## **DC CHARACTERISTICS**

Parameter		Symbol	Min	Max	Unit
Input Leakage Current (All Inputs, V <sub>in</sub> = 0 to V <sub>DD</sub> )		l <sub>lkg(l)</sub>	_	± 1.0	μΑ
Output Leakage Current ( $\overline{E} = V_{IH}$ , $V_{Out} = 0$ to $V_{DD}$ )		l <sub>lkg(O)</sub>	_	± 1.0	μΑ
Output Low Voltage	$(I_{OL} = + 4.0 \text{ mA})$ $(I_{OL} = + 100 \mu\text{A})$	VOL	_	0.4 V <sub>SS</sub> + 0.2	V
Output High Voltage	$(I_{OH} = -4.0 \text{ mA})$ $(I_{OH} = -100 \mu\text{A})$	Vон	2.4 V <sub>DD</sub> – 0.2	_	V

## POWER SUPPLY CURRENTS (See Note 1)

Parameter		Symbol	6323A-10	6323A-12	6323A-15	Unit	Notes
AC Active Supply Current (I <sub>Out</sub> = 0 mA) (V <sub>DD</sub> = max, f = f <sub>max</sub> )	Commerical Industrial	I <sub>DDA</sub>	140 150	135 140	130 135	mA	2
AC Standby Current ( $\overline{E} = V_{IH}, V_{DD} = max, f = f_{max}$ )	Commerical Industrial	ISB1	40 45	35 40	30 35	mA	2
$\label{eq:cmos}  \begin{aligned} & \underline{CMOS} \   Standby \   Current \   (V_{DD} = max,  f = 0 \ MHz, \\ & \overline{E} \geq V_{DD} - 0.2 \ V,  V_{in} \leq V_{SS} + 0.2 \ V, \\ & or \geq V_{DD} - 0.2 \ V) \end{aligned}$	Commerical Industrial	I <sub>SB2</sub>	5 5	5 5	5 5	mA	

#### NOTES:

- 1. Typical current = 25°C @ 3.3 V.
- 2. Reference AC Operating Conditions and Characteristics for input and timing ( $V_{IH}/V_{IL}$ ,  $t_f/t_f$ , pulse level 0 to 3.0 V,  $V_{IH} = 3.0$  V,  $V_{IL} = 0$  V).

## CAPACITANCE (f = 1.0 MHz, dV = 3.0 V, T<sub>A</sub> = 25°C, Periodically Sampled Rather Than 100% Tested)

Parameter	Symbol	Тур	Max	Unit
Address Input Capacitance	C <sub>in</sub>	_	6	pF
Control Input Capacitance	C <sub>in</sub>	_	6	pF
Input/Output Capacitance	C <sub>I/O</sub>	_	8	pF

<sup>\*\*</sup>  $V_{IH}$  (max) =  $V_{DD}$  + 0.3 V dc;  $V_{IH}$  (max) =  $V_{DD}$  + 2.0 V ac (pulse width  $\leq$  20 ns) for I  $\leq$  20.0 mA.

## **AC OPERATING CONDITIONS AND CHARACTERISTICS**

(V<sub>DD</sub> = 3.3 V  $\pm$  0.3 V, T<sub>A</sub> = 0 to +70°C, Unless Otherwise Noted) (T<sub>A</sub> = - 40 to + 85°C for Industrial Temperature Offering)

Logic Input Timing Measurement Reference Level 1.50 V	Output Timing Reference Level
Logic Input Pulse Levels 0 to 3.0 V	Output Load See Figure
Input Rise/Fall Time	

## READ CYCLE TIMING (See Notes 1, 2, 3, and 4)

		МСМ63	23A-10	MCM6323A-12		MCM63	23A-15		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit	Notes
Read Cycle Time	tavav	10	_	12	_	15	_	ns	5
Address Access Time	tAVQV	_	10	_	12	_	15	ns	
Enable Access Time	t <sub>ELQV</sub>	_	10	_	12	_	15	ns	
Output Enable Access Time	tGLQV	_	4	_	5	_	6	ns	6
Output Hold from Address Change	tAXQX	3	_	3	_	3	_	ns	
Enable Low to Output Active	t <sub>ELQX</sub>	3	_	3	_	3	_	ns	6, 7, 8
Output Enable Low to Output Active	tGLQX	0	_	0	_	0	_	ns	6, 7, 8
Enable High to Output High–Z	<sup>t</sup> EHQZ	_	4		5	_	6	ns	6, 7, 8
Output Enable High to Output High–Z	<sup>t</sup> GHQZ	_	4		5	_	6	ns	6, 7, 8
Byte Enable Access Time	t <sub>BLQV</sub>	_	4	_	5	_	6	ns	
Byte Enable Low to Output Active	tBLQX	0	_	0	_	0	_	ns	6, 7, 8
Byte High to Output High-Z	<sup>t</sup> BHQZ	0	5	0	5	0	5	ns	6, 7, 8

#### NOTES:

- 1.  $\overline{W}$  is high for read cycle.
- 2. For common I/O applications, minimization, or elimination of bus contention conditions is necessary during read and write cycles.
- 3. Device is continuously selected ( $\overline{E} = V_{IL}$ ,  $\overline{G} = V_{IL}$ , and  $\overline{LB}$  and/or  $\overline{UB} = V_{IL}$ ).
- 4. Addresses valid prior to or coincident with  $\overline{\mathsf{E}}$  going low.
- 5. All read cycle timings are referenced from the last valid address to the first transitioning address.
- 6. Transition is measured 200 mV from steady-state voltage.
- 7. At any given voltage and temperature, tehQZ (max) < telQX (min), and tGHQZ (max) < tGLQX (min), both for a given device and from device to device.
- 8. This parameter is sampled and not 100% tested.

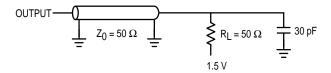


Figure 1. Equivalent AC Test Load

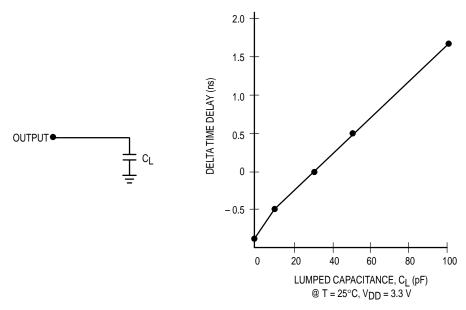


Figure 2. Lumped Capacitive Load and Typical Derating Curve

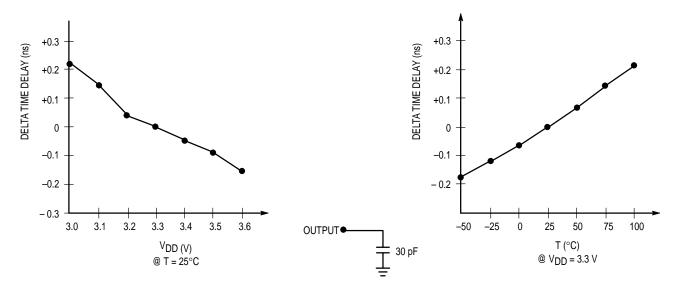
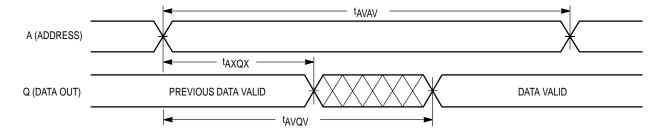
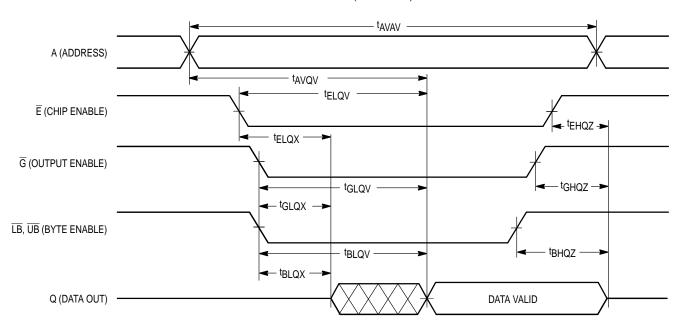


Figure 3. Derating Across Temperature and Voltage

## READ CYCLE 1 (See Note 7)



## READ CYCLE 2 (See Note 8)



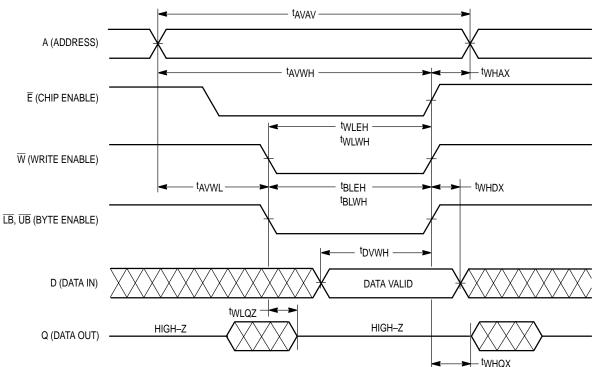
## WRITE CYCLE 1 (W Controlled, See Notes 1 and 2)

		MCM63	23A-10	MCM6323A-12		MCM63	23A-15		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit	Notes
Write Cycle Time	tavav	10	_	12	_	15	_	ns	3
Address Setup Time	<sup>t</sup> AVWL	0		0	_	0	_	ns	
Address Valid to End of Write	tAVWH	8	_	9	_	10	_	ns	
Write Pulse Width	tWLWH, tWLEH	8	_	9	_	10	_	ns	
Byte Pulse Width	<sup>t</sup> BLWH <sup>,</sup> <sup>t</sup> BLEH	8	_	9	_	10	_	ns	
Data Valid to End of Write	tDVWH	4	_	5	_	6	_	ns	
Data Hold Time	tWHDX	0	_	0	_	0	_	ns	
Write Low to Data High–Z	tWLQZ	0	4	0	5	0	6	ns	4, 5, 6
Write High to Output Active	tWHQX	3	_	3	_	3	_	ns	4, 5, 6
Write Recovery Time	tWHAX	0	_	0	_	0	_	ns	

## NOTES:

- 1. A write occurs during the overlap of  $\overline{E}$  low,  $\overline{W}$  low, and  $\overline{LB}$  and/or  $\overline{UB}$  low.
- 2. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycles.
- 3. All write cycle timings are referenced from the last valid address to the first transitioning address.
- 4. Transition is measured 200 mV from steady-state voltage.
- 5. At any given voltage and temperature, t<sub>WLQZ</sub> max < t<sub>WHQX</sub> min both for a given device and from device to device.
- 6. This parameter is sampled and not 100% tested.

## WRITE CYCLE 1 (W Controlled)



## WRITE CYCLE 2 (E Controlled, See Notes 1 and 2)

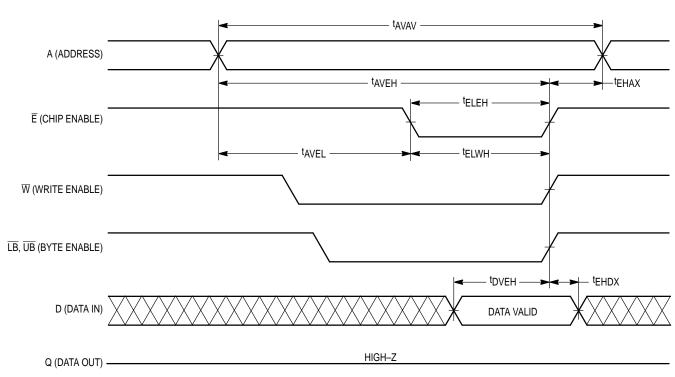
		MCM6323A-10 MCM6323A-12		23A-12	MCM6323A-15				
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit	Notes
Write Cycle Time	t <sub>AVAV</sub>	10	_	12	_	15	_	ns	3
Address Setup Time	<sup>t</sup> AVEL	0	_	0	_	0	_	ns	
Address Valid to End of Write	<sup>t</sup> AVEH	8	_	9	_	10	_	ns	
Enable to End of Write	tELEH, tELWH	8	_	9	_	10	_	ns	4, 5
Data Valid to End of Write	<sup>t</sup> DVEH	4	_	5	_	6	_	ns	
Data Hold Time	tEHDX	0	_	0	_	0	_	ns	
Write Recovery Time	<sup>t</sup> EHAX	0	_	0	_	0	_	ns	

#### NOTES:

- 1. A write occurs during the overlap of  $\overline{E}$  low,  $\overline{W}$  low, and  $\overline{LB}$  and/or  $\overline{UB}$  low.
- 2. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycles.
- 3. All write cycle timings are referenced from the last valid address to the first transitioning address.
- 4. If  $\overline{E}$  goes low coincident with or after  $\overline{W}$  goes low, the output will remain in a high impedance condition.
- 5. If  $\overline{E}$  goes high coincident with or before  $\overline{W}$  goes high, the output will remain in a high impedance condition.

## **WRITE CYCLE 2**

(E Controlled)

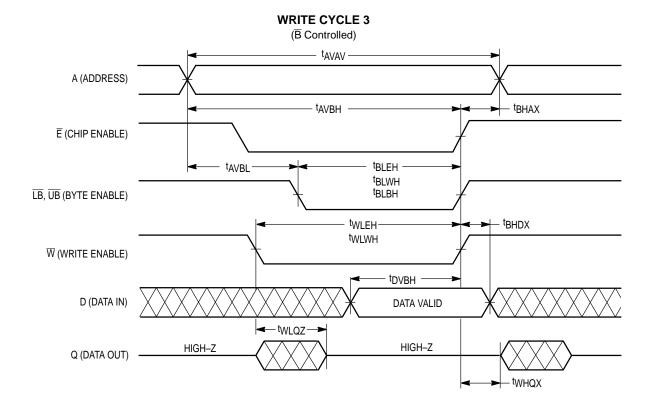


## WRITE CYCLE 3 (B Controlled, See Notes 1 and 2)

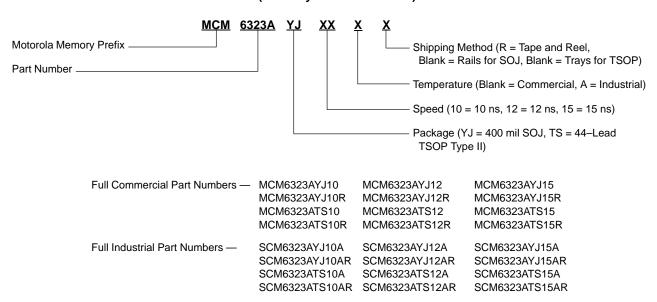
		MCM63	23A-10	MCM63	23A-12	MCM63	23A-15		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Unit	Notes
Write Cycle Time	t <sub>AVAV</sub>	10	_	12	_	15	_	ns	3
Address Setup Time	<sup>t</sup> AVBL	0	_	0	_	0	_	ns	
Address Valid to End of Write	<sup>t</sup> AVBH	8	_	9	_	10	_	ns	
Write Pulse Width	tWLWH, tWLEH	8	_	9	_	10	_	ns	
Byte Pulse Width	tBLWH, tBLEH, tBLBH	8	_	9	_	10	_	ns	
Data Valid to End of Write	<sup>t</sup> DVBH	5	_	6	_	7	_	ns	
Data Hold Time	<sup>t</sup> BHDX	0	_	0	_	0	_	ns	
Write Low to Data High–Z	tWLQZ	0	4	0	5	0	6	ns	4, 5, 6
Write High to Output Active	tWHQX	3	_	3	_	3	_	ns	4, 5, 6
Write Recovery Time	<sup>t</sup> BHAX	0	_	0	_	0	_	ns	

#### NOTES:

- 1. A write occurs during the overlap of  $\overline{E}$  low,  $\overline{W}$  low, and  $\overline{LB}$  and/or  $\overline{UB}$  low.
- 2. For common I/O applications, minimization or elimination of bus contention conditions is necessary during read and write cycles.
- 3. All write cycle timings are referenced from the last valid address to the first transitioning address.
- 4. Transition is measured 200 mV from steady-state voltage.
- 5. At any given voltage and temperature,  $t_{WLQZ}$  max <  $t_{WHQX}$  min both for a given device and from device to device.
- 6. This parameter is sampled and not 100% tested.

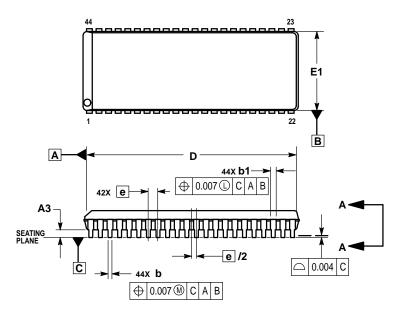


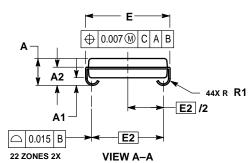
## ORDERING INFORMATION (Order by Full Part Number)



## **PACKAGE DIMENSIONS**

YJ PACKAGE 400 MIL SOJ **CASE 919-01** 



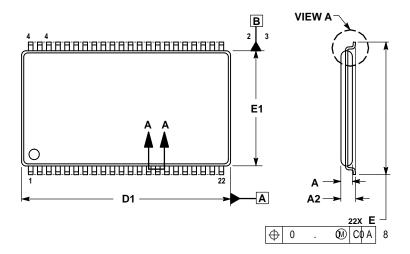


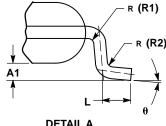
#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: INCH. DIMENSION D DOES NOT INCLUDE MOLD FLASH, TIE BAR BURRS AND GATE BURRS. MOLD FLASH, TIE BAR BURRS AND GATE BURRS SHALL NOT EXCEED 0.006 PER END. DIMENSION 3. E1 DOES NOT INCLUDE INTERLEAD FLASH. INTERLEAD FLASH SHALL NOT EXCEED 0.010
- PER SIDE.
  THE PACKAGE TOP MAY BE SMALLER THAN THE THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM. DIMENSIONS D AND E1 AND, HENCE, DATUMS A AND B, ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH,
- BURNS, SAIE BURNS AND INITERLEAD FLASH,
  BUT INCLUDING ANY MISMATCH BETWEEN THE
  TOP AND BOTTOM OF THE PLASTIC BODY.
  DIMENSION 51 DOES NOT INCLUDE DAMBAR
  PROTRUSION OR INTRUSION. THE DAMBAR
  PROTRUSION(S) SHALL NOT CAUSE THE
  SHOULDER WIDTH TO EXCEED 51 MAX BY MORE THAN 0.005. THE DAMBAR INTRUSION(S)
  SHALL NOT REDUCE THE SHOULDER WIDTH TO LESS THAN 0.001 BELOW b1 MIN.

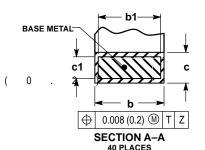
	INCHES				
DIM	MIN	MAX			
Α	0.128	0.148			
A1	0.025				
A2	0.082				
A3	0.035	0.045			
b	0.015	0.020			
b1	0.026	0.032			
D	1.120	1.130			
E	0.435	0.445			
E1	0.395	0.405			
E2	0.370	BSC			
е	0.050 BSC				
R1	0.030	0.040			

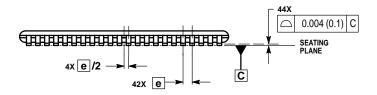
**TS PACKAGE** 44-LEAD **TSOP TYPE II** CASE 924A-01





**DETAIL A** ROTATED 90 ° CLOCKWISE





#### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: INCH.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE MOLD PROTRUSION IS 0.006 (0.015) PER SIDE.

  4. DIMENSION 6 DOES NOT INCLUDE DAMBAR
- PROTRUSIONS. DAMBAR PROTRUSIONS SHALL NOT ALLOW THE b DIMENSION TO EXCEED 0.023

	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α		0.050	_	1.270	
A1	0.002	0.006	0.051	0.152	
A2	0.038	0.042	0.965	1.067	
b	0.012	0.018	0.305	0.457	
b1	0.012	0.016	0.305	0.406	
С	0.005	0.008	0.127	0.203	
c1	0.004	0.006	0.101	0.152	
D1	0.721	0.729	18.313	18.517	
a	0.0315 BSC		0.800 BSC		
Е	0.456	0.470	11.582	11.938	
E1	0.396	0.404	10.058	10.262	
L	0.016	0.023	0.406	0.584	
R1	0.004 REF		0.100 REF		
R2	0.004	0.004 REF		REF	
θ	0 °	5 °	0 °	5 °	

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